

## PRELIMINARY DATA

### DUAL 2-WIDE 2-INPUT AND-OR-INVERTER GATE

- MEDIUM-SPEED OPERATION -  $t_{pHL} = 90$  ns;  $t_{pLH} = 125$  ns (TYP.) AT 10V
- INDIVIDUAL INHIBIT CONTROLS
- STANDARDIZED SYMMETRICAL OUTPUT CHARACTERISTICS
- QUIESCENT CURRENT SPECIFIED TO 20V
- MAXIMUM INPUT CURRENT OF 1  $\mu$ A AT 18V (FULL PACKAGE-TEMPERATURE RANGE)
- 5V, 10V, AND 15V PAFAMETRIC RATINGS

The **HCC 4085B** (extended temperature range) and **HCF 4085B** (intermediate temperature range) are monolithic integrated circuit, available in 14-lead dual in-line plastic or ceramic package and ceramic flat package.

The **HCC/HCF 4085B** contains a pair of AND-OR-INVERT gates, each consisting of two 2-input AND gates driving a 3-input NOR gate. Individual inhibit controls are provided for both A-O-I gates.

### ABSOLUTE MAXIMUM RATINGS

$V_{DD}$ *	Supply voltage	-0.5 to 20	V
$V_I$	Input voltage	-0.5 to $V_{DD} + 0.5$	V
$I_I$	DC input current: (any one input)	$\pm 10$	mA
$P_{tot}$	Total power dissipation (per package)	200	mW
	Dissipation per output transistor		
	for $T_{op}$ = full package-temperature range	100	mW
$T_{op}$	Operating temperature: for <b>HCC</b> types	-55 to 125	$^{\circ}$ C
	for <b>HCF</b> types	-40 to 85	$^{\circ}$ C
$T_{stg}$	Storage temperature	-65 to 150	$^{\circ}$ C

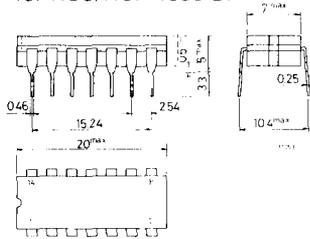
\* All voltage values are referred to  $V_{SS}$  pin voltage

### ORDERING NUMBERS:

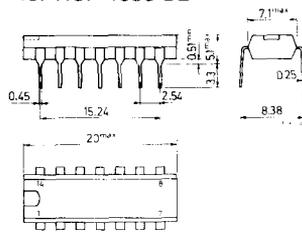
- HCC 4085 BD for dual in-line ceramic package
- HCC 4085 BF for dual in-line ceramic package, frit seal
- HCC 4085 BK for ceramic flat package
- HCF 4085 BE for dual in-line plastic package
- HCF 4085 BF for dual in-line ceramic package, frit seal

## MECHANICAL DATA (dimensions in mm)

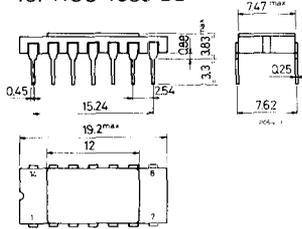
Dual in-line ceramic package  
for HCC/HCF 4085 BF



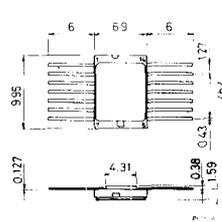
Dual in-line plastic package  
for HCF 4085 BE



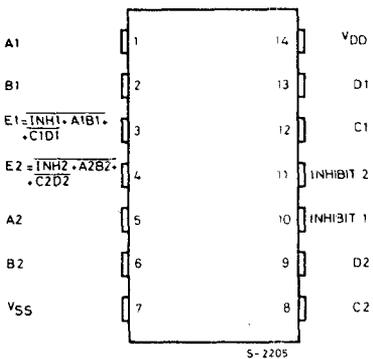
Dual in-line ceramic package  
for HCC 4085 BD



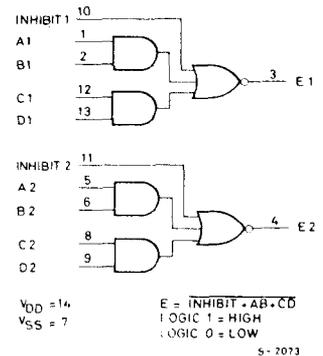
Ceramic flat package  
for HCC 4085 BK



## CONNECTION DIAGRAM



## LOGIC DIAGRAM

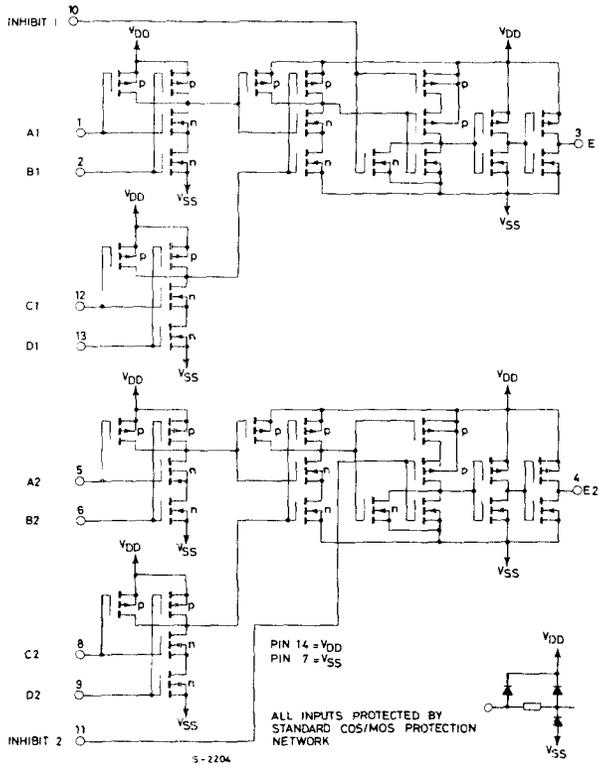


## RECOMMENDED OPERATING CONDITIONS

$V_{DD}$	Supply voltage	3 to 18	V
$V_I$	Input voltage	0 to $V_{DD}$	V
$T_{op}$	Operating temperature: for HCC types for HCF types	-55 to 125 -40 to 85	°C °C

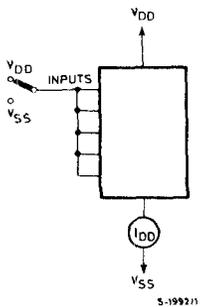


### SCHEMATIC DIAGRAM

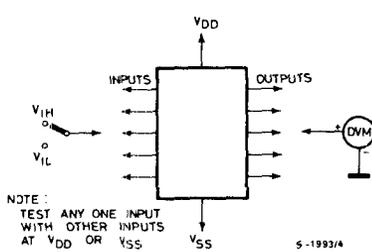


### TEST CIRCUITS

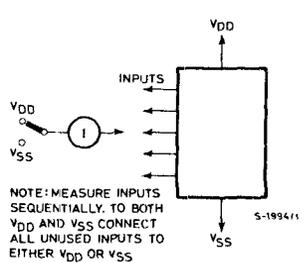
Quiescent device current



Input voltage



Input current



### STATIC ELECTRICAL CHARACTERISTICS (over recommended operating conditions)

Parameter	Test conditions				Values							Unit
	V <sub>I</sub> (V)	V <sub>O</sub> (V)	I <sub>O</sub>   ( $\mu$ A)	V <sub>DD</sub> (V)	T <sub>Low</sub> *		25°C			T <sub>High</sub> *		
					Min.	Max.	Min.	Typ.	Max.	Min.	Max.	
I <sub>L</sub> Quiescent supply current	0/ 5			5		1		0.02	1		30	$\mu$ A
	0/10			10		2		0.02	2		60	
	0/15			15		4		0.02	4		120	
	0/20			20		20		0.04	20		600	
V <sub>OH</sub> Output high voltage	0/ 5		< 1	5	4.95		4.95			4.95		V
	0/10		< 1	10	9.95		9.95			9.95		
	0/15		< 1	15	14.95		14.95			14.95		
V <sub>OL</sub> Output low voltage	5/0		< 1	5		0.05			0.05		0.05	V
	10/0		< 1	10		0.05			0.05		0.05	
	15/0		< 1	15		0.05			0.05		0.05	
V <sub>IH</sub> Input high voltage		0.5/4.5	< 1	5	3.5		3.5			3.5		V
		1/9	< 1	10	7		7			7		
		15/13.5	< 1	15	11		11			11		
V <sub>IL</sub> Input low voltage		4.5/0.5	< 1	5		1.5			1.5		1.5	V
		9/1	< 1	10		3			3		3	
		13.5/15	< 1	15		4			4		4	
I <sub>OH</sub> Output drive current	HCC types	0/ 5	2.5		5	-2		-1.6	-3.2		-1.15	V
		0/ 5	4.6		5	-0.64		-0.51	-1		-0.36	
		0/10	9.5		10	-1.6		-1.3	-2.6		-0.9	
	0/15	13.5		15	-4.2		-3.4	-6.8		-2.4		
	HCF types	0/ 5	2.5		5	-1.8		-1.6	-3.2		-1.3	
		0/ 5	4.6		5	-0.61		-0.51	-1		-0.42	
0/10		9.5		10	-1.5		-1.3	-2.6		-1.1		
I <sub>OL</sub> Output sink current	HCC types	0/ 5	0.4		5	0.64		0.51	1		0.36	V
		0/10	0.5		10	1.6		1.3	2.6		0.9	
		0/15	1.5		15	4.2		3.4	6.8		2.4	
	HCF types	0/ 5	0.4		5	0.61		0.51	1		0.42	
		0/10	0.5		10	1.5		1.3	2.6		1.1	
		0/15	1.5		15	4		3.4	6.8		2.8	
I <sub>IH</sub> , I <sub>IL</sub> Input leakage current	0/18	Any input	18		$\pm$ 0.1		$\pm$ 10 <sup>-5</sup>	$\pm$ 0.1		$\pm$ 1	$\mu$ A	
C <sub>I</sub> Input capacitance		Any input					5	7.5			pF	

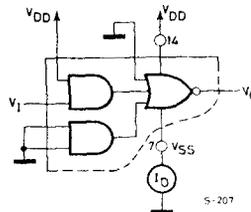
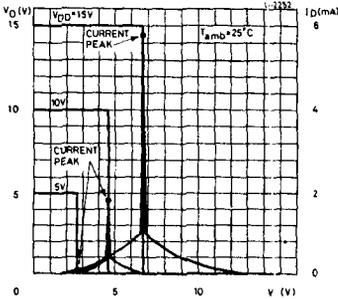
\* T<sub>Low</sub> = - 55°C for HCC device; - 40°C for HCF device.  
 \* T<sub>High</sub> = +125°C for HCC device; + 85°C for HCF device.  
 The Noise Margin for both "1" and "0" level is: 1V min. with V<sub>DD</sub>= 5V  
 2V min. with V<sub>DD</sub>= 10V  
 2.5V min. with V<sub>DD</sub>= 15V



**DYNAMIC ELECTRICAL CHARACTERISTICS** ( $T_{amb} = 25^{\circ}\text{C}$ ,  $C_L = 50\text{ pF}$ ,  $R_L = 200\text{ k}\Omega$ , typical temperature coefficient for all  $V_{DD}$  values is  $0.3\%/^{\circ}\text{C}$ , all input rise and fall times =  $20\text{ ns}$ )

Parameter	Test conditions	Values			Unit	
		$V_{DD}$ (V)	Min.	Typ.		Max.
$t_{PHL}$ Propagation delay time (Data)		5		225	450	ns
		10		90	180	
		15		65	130	
$t_{PLH}$ Propagation delay time (Data)		5		310	620	
		10		125	250	
		15		90	180	
$t_{PHL}$ Propagation delay time (Inhibit)		5		150	300	ns
		10		60	120	
		15		40	80	
$t_{PLH}$ Propagation delay time (Inhibit)		5		250	500	
		10		100	200	
		15		70	140	
$t_{TLH}$ , $t_{THL}$ Transition time		5		100	200	ns
		10		50	100	
		15		40	80	

Typical voltage and current transfer characteristics with test circuit



Minimum and maximum voltage transfer characteristics with test circuit

